650V, 12A, 148mΩ N-channel Power Super Junction MOSFET

JMH65R190PFFD

Features

- $\bullet \;\;$ Excellent $R_{DS(ON)}$ and Low Gate Charge
- 100% UIS Tested
- 100% ΔVds Tested
- Halogen-free; RoHS-compliant

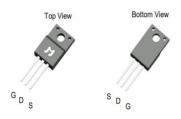
Product Summary

Parameters	Value	Unit
V_{DSS}	650	V
$V_{GS(th)_Typ}$	3.6	V
$I_{D}(@V_{GS}=10V)$	12	Α
$R_{DS(ON)_Typ}(@V_{GS}=10V$	148	mΩ



Applications

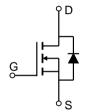
- SMPS with PFC
- Flyback and LLC topologies
- Silver ATX,adapter,TV,lighting,Telecom







Pin Assignment



Schematic Diagram

Ordering Information

Device	Marking	MSL	Form	Package	Tube(pcs)	Per Carton (pcs)
JMH65R190PFFD-U	H65R190PF	N/A	Tube	TO-220FP	50	5000

Absolute Maximum Ratings (@ T_C = 25°C unless otherwise specified)

	<u> </u>		,	
Symbol	Parameter		Value	Unit
V _{DS}	Drain-to-Source Voltage		650	V
V_{GS}	Gate-to-Source Voltage		±30	V
I _D C	Continuous Drain Current	$T_C = 25^{\circ}C$	12	۸
	Continuous Drain Current	$T_{\rm C} = 100^{\circ}{\rm C}$	7.6	A
I _{DM}	Pulsed Drain Current (1)		Refer to Fig.4	А
E _{AS}	Single Pulsed Avalanche Energy (2)		65	mJ
P _D	Power Dissipation	$T_C = 25^{\circ}C$	71	W
		$T_C = 100$ °C	28	VV
T_{J} , T_{STG}	Junction & Storage Temperature Range		-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	58	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.8	C/ VV



Electrical Characteristics (T_J = 25°C unless otherwise specified)

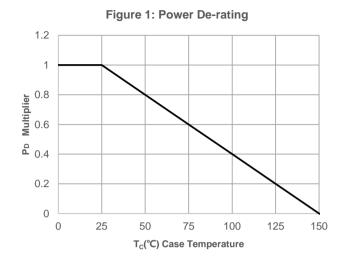
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Characteristics						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	650	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 650V, V_{GS} = 0V$	-	-	10.0	μА
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 30V$	-	-	±100	nA
On Cha	racteristics					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5	3.6	4.6	V
R _{DS(ON)}	Static Drain-Source ON-Resistance (4)	$V_{GS} = 10V, I_{D} = 10A$	-	148	190	mΩ
Dynam	ic Characteristics					
R_g	Gate Resistance	f = 1MHz	ı	4.9	-	Ω
C _{iss}	Input Capacitance	., ., ., ., ., ., ., ., ., ., ., ., ., .	1084	1517	2049	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 325V,$ f = 1MHz	28	39	52	pF
C_{rss}	Reverse Transfer Capacitance	1 - 111112	-	5.9	-	pF
Q_g	Total Gate Charge		23	32	43	nC
Q_{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 325V, I_D = 10A$	-	10	-	nC
Q_{gd}	Gate Drain("Miller") Charge	V _{DS} = 020 V, I _D = 10/1	-	11	-	nC
Switchi	ing Characteristics					
t _{d(on)}	Turn-On DelayTime			36	Ι.	ns
t _r	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 310V$		38	_	ns
t _{d(off)}	Turn-Off DelayTime	I_{D} = 10A, R_{GEN} = 24 Ω		100	_	ns
t _f	Turn-Off Fall Time	_	-	30	-	ns
Body D	liode Characteristics					
I _S	Maximum Continuous Body Diode Forward Current		-	-	12	Α
I _{SM}	Maximum Pulsed Body Diode Forward Current		-	-	48	Α
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 10A$	-		1.2	V
trr	Body Diode Reverse Recovery Time	1 404 45/-5 4004/	94	131	177	ns
Qrr	Body Diode Reverse Recovery Charge	$I_F = 10A$, di/dt = 100A/us	-	851	-	nC

Notes:

- 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
- 2. E_{AS} condition: Starting T_J =25C, V_{DD} =50V, V_{GS} =10V, R_G =25ohm, L=10mH, I_{AS} =3.6A, V_{DD} =0V during time in avalanche.
- $3.~R_{BJA}$ is measured with the device mounted on FR-4 substrate PC board, 20z copper, with minimum recommended pad layout.
- 4. Pulse Test: Pulse Width≤300μs, Duty Cycle≤0.5%.



Typical Performance Characteristics



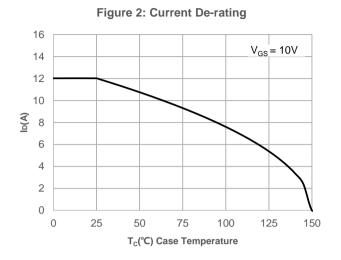
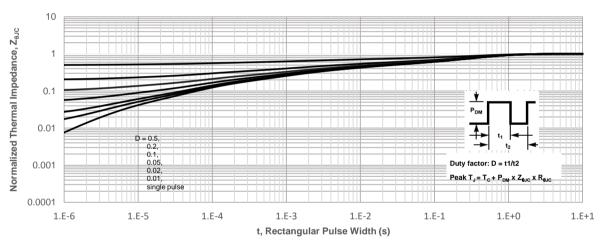
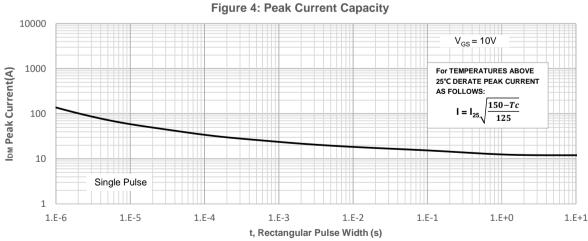


Figure 3: Normalized Maximum Transient Thermal Impedance







Typical Performance Characteristics

Figure 5: Output Characteristics

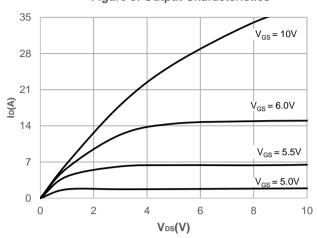


Figure 6: Typical Transfer Characteristics

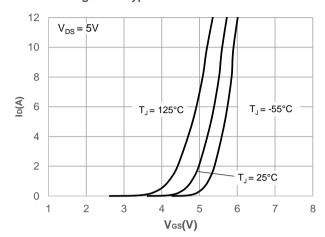


Figure 7: On-resistance vs. Drain Current

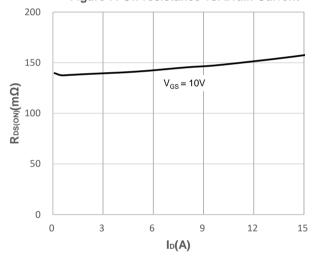


Figure 8: Body Diode Characteristics

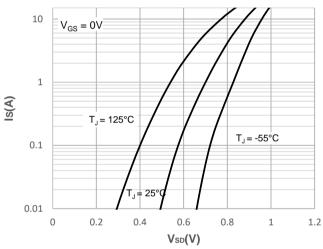


Figure 9: Gate Charge Characteristics

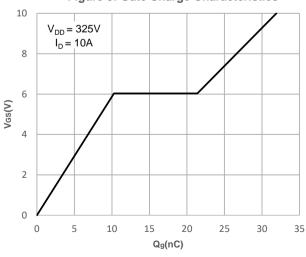
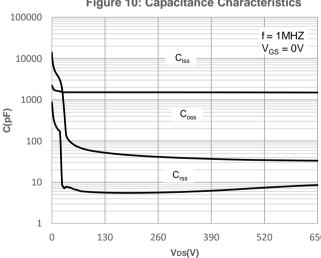


Figure 10: Capacitance Characteristics





Typical Performance Characteristics

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

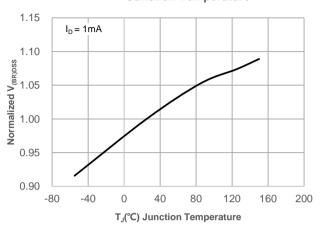


Figure 13: Normalized Threshold Voltage vs.
Junction Temperature

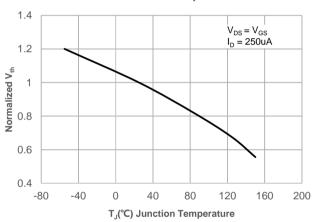


Figure 15: Maximum Safe Operating Area

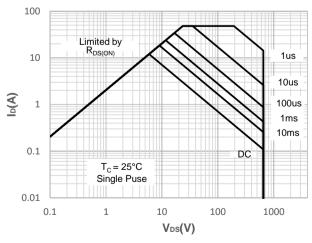
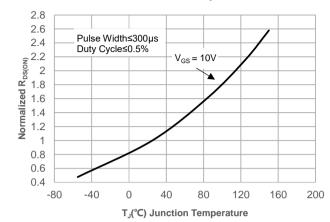
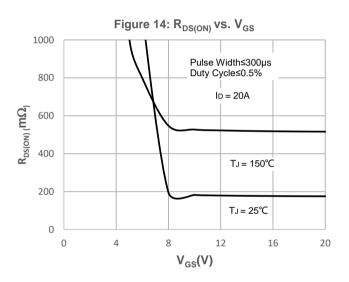


Figure 12: Normalized on Resistance vs.
Junction Temperature







Test Circuit

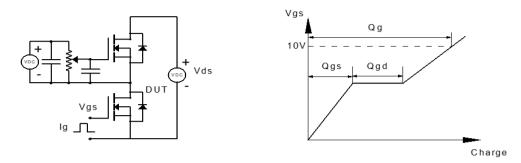


Figure 1: Gate Charge Test Circuit & Waveform

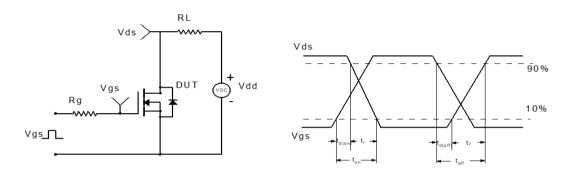


Figure 2: Resistive Switching Test Circuit & Waveform

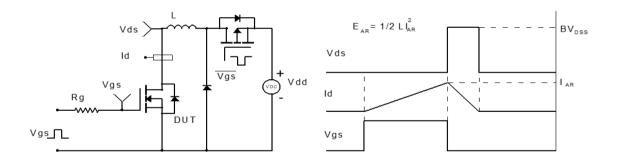


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

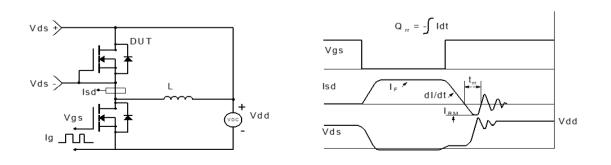
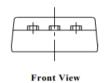


Figure 4: Diode Recovery Test Circuit & Waveform

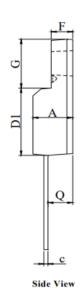


Package Mechanical Data(TO-220F-3L)

Package Outline



Top View



DIM.	N	IILLIMETE	R	
DIM.	MIN.	NOM.	MAX.	
A	4.50	4.70	4.90	
D	15.20	15.87	16.10	
D1	8.80		9.50	
Е	9.70	10.10	10.40	
F	2.44		2.75	
ь	0.70	0.80	0.91	
b1	1.10	1.35	1.55	
с	0.45	0.50	0.65	
e	2.54 BSC			
G	6.40	6.70	6.90	
L	12.00	13.10	14.50	
L1	3.13		3.57	
Q	2.60	2.75	2.85	
Q1	3.20	3.30	3.40	
R	3.05		3.28	

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